

Notice of References Cited	Application/Control No. 10/798,009	Applicant(s)/Patent Under Reexamination GARRATT ET AL.	
	Examiner John J. Zimmerman	Art Unit 1775	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,061,327	10-1991	Denzer et al.	148/693
*	B	US-5,194,102	03-1993	Wyss, Rebecca K.	148/695
*	C	US-5,826,456	10-1998	Kawazoe et al.	72/253.1
*	D	US-5,863,359	01-1999	Karabin et al.	148/437
*	E	US-6,231,995	05-2001	Yamashita et al.	428/598
*	F	US-6,325,869	12-2001	Liu et al.	148/439
*	G	US-2001/0020501	09-2001	Liu et al.	148/690
*	H	US-2002/0014287	02-2002	YOSHIHARA et al.	148/417
*	I	US-2002/0043640	04-2002	Takemoto et al.	251/368
*	J	US-2003/0008165	01-2003	Kawai et al.	428/586
*	K	US-522,736	07-1894	Name not available	52/729.2
*	L	US-4,294,625	10-1981	Hyatt et al.	148/550
*	M	US-4,336,075	06-1982	Quist et al.	148/550

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/798,009		Applicant(s)/Patent Under Reexamination GARRATT ET AL.	
	Examiner John J. Zimmerman		Art Unit 1775	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,071,492	12-1991	Parker et al.	148/517
*	B	US-Reissue 34008	07-1992	Quist et al.	148/2
*	C	US-5,221,377	06-1993	Hunt et al.	148/417
*	D	US-5,759,302	06-1998	Nakai et al.	148/415
*	E	US-5,865,911	02-1999	Miyasato et al.	148/439
*	F	US-5,865,914	02-1999	Karabin et al.	148/693
*	G	US-5,980,206	11-1999	Hunter et al.	416/134A
*	H	US-6,113,711	09-2000	Armanie et al.	148/689
*	I	US-6,277,219	08-2001	Heinz et al.	148/552
*	J	US-2002/0000492	01-2002	Schmidt, Hans-Juergen	244/125
*	K	US-6,364,250	04-2002	Brinck et al.	244/119
*	L	US-6,444,058	09-2002	Liu et al.	148/439
*	M	US-2002/0150498	10-2002	Chakrabarti et al.	420/532

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	11-071624	03-1999	Japan	Yamashita	---
*	O	04-022508	01-1992	Japan	---	---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	K.R. Van Horn, "Factors Affecting Directional Properties in Aluminum Wrought Products", pp. 38-76, TRANSACTIONS OF THE ASM, Vol. 47, presented at the 36th Annual Convention of the Society, Chicago, IL, November 3, 1954.			
*	V	H.Y. Hunsicker, "New Graphic Method for Analysis of Hot Deformation and Effects on Directional Properties", pp. 29-42, TRANSACTIONS OF THE METALLURGICAL SOCIETY OF AIME, Vol. 245, January 1969.			
*	W	P.I. Welch et al., "The Effect of Texture on Fatigue Crack Propagation in Aluminum Alloy 7075", pp. 332-335, ALUMINUM, 61 Jahrg 1985.			
*	X	D.L. Chen et al., "Fatigue Crack Growth Behavior of X2095 Al-Li Alloy", pp. 1079-1086, International Journal of Fatigue 21, 1999.			

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.